

DEVELOPMENT OF AN ATOMIC FORCE MICROSCOPE SCANNER

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A Thesis Submitted in
Partial Fulfilment of the
Requirements for the Degree of

Master of Science
in Mechanical Engineering

at

Technical University of Łódź
Under Supervision of Professor Jan Awrejcewicz

The Master Project was Carried Out at
Delft University of Technology
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Łódź

December 2009

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